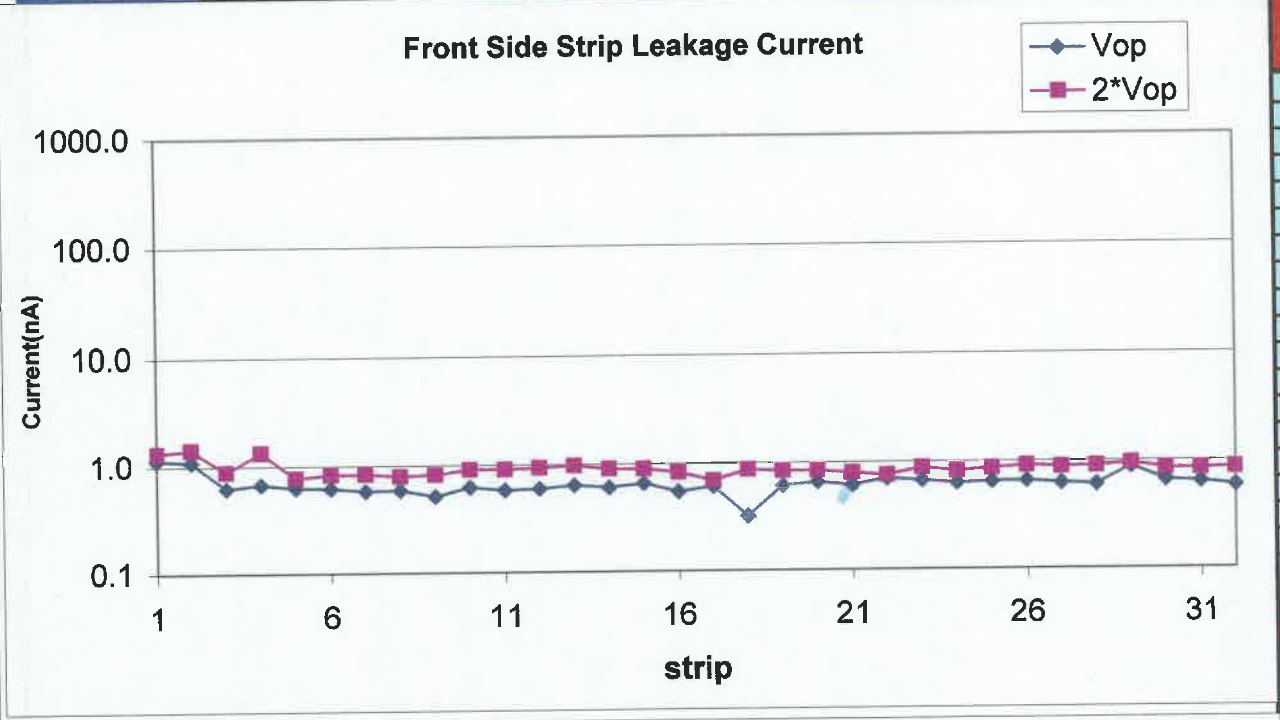
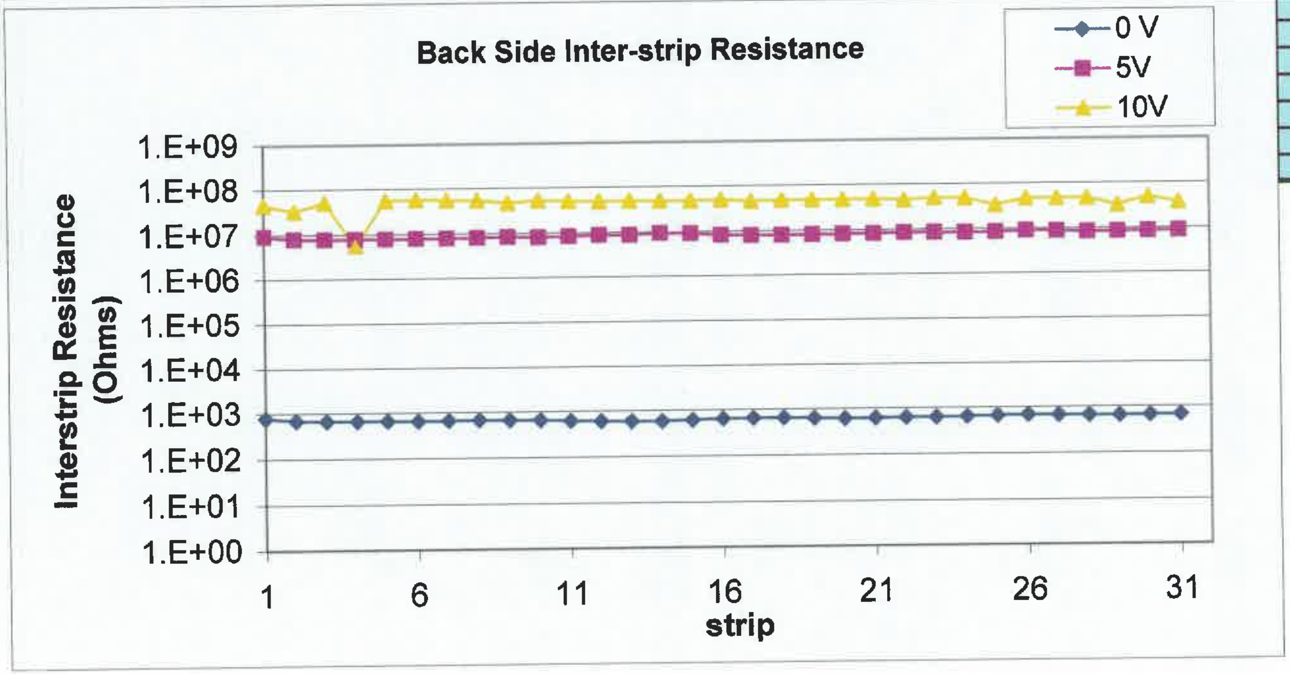
Detector Profile BB7-65

Wafer No.: 2435-2 **Thickness:** 61 um **Vop:** 5 Volts

Front Side Data

Strip	Current(nA)	
	Vop	2*Vop
1	1.15	1.34
2	1.10	1.44
3	0.63	0.89
4	0.68	1.35
5	0.63	0.78
6	0.62	0.83
7	0.58	0.84
8	0.59	0.80
9	0.52	0.83
10	0.62	0.92
11	0.58	0.92
12	0.60	0.95
13	0.64	0.98
14	0.61	0.91
15	0.66	0.90
16	0.55	0.84
17	0.61	0.70
18	0.32	0.88
19	0.61	0.85
20	0.66	0.84
21	0.62	0.80
22	0.70	0.76
23	0.67	0.89
24	0.63	0.82
25	0.65	0.87
26	0.66	0.92
27	0.63	0.89
28	0.61	0.90
29	0.99	0.85
30	0.66	0.86
31	0.64	0.85
32	0.59	0.87
Total	20.98	29.04





Back Side Data

Strip	Back Resistance (Ω)		
	0V	5V	10V
1	7.9E+02	9.3E+06	4.6E+07
2	6.9E+02	8.1E+06	3.4E+07
3	6.6E+02	7.9E+06	5.2E+07
4	6.7E+02	7.9E+06	5.7E+06
5	6.7E+02	7.9E+06	5.7E+07
6	6.5E+02	8.1E+06	5.9E+07
7	6.6E+02	8.0E+06	5.7E+07
8	6.7E+02	8.2E+06	5.6E+07
9	6.7E+02	8.4E+06	4.8E+07
10	6.5E+02	8.1E+06	5.4E+07
11	6.2E+02	8.5E+06	5.2E+07
12	6.0E+02	8.9E+06	5.0E+07
13	5.9E+02	8.8E+06	5.1E+07
14	5.9E+02	9.5E+06	5.0E+07
15	6.1E+02	9.2E+06	4.9E+07
16	6.5E+02	8.4E+06	5.1E+07
17	6.5E+02	8.1E+06	4.7E+07
18	6.5E+02	8.1E+06	4.8E+07
19	6.3E+02	8.2E+06	4.8E+07
20	6.1E+02	8.3E+06	4.8E+07
21	6.2E+02	8.3E+06	4.9E+07
22	6.3E+02	8.7E+06	4.6E+07
23	6.4E+02	8.5E+06	5.1E+07
24	6.4E+02	8.4E+06	4.9E+07
25	6.6E+02	8.6E+06	3.5E+07
26	6.9E+02	9.2E+06	4.8E+07
27	6.7E+02	8.9E+06	4.8E+07
28	6.6E+02	8.4E+06	4.7E+07
29	6.6E+02	8.5E+06	3.3E+07
30	6.7E+02	8.8E+06	5.0E+07
31	6.8E+02	8.9E+06	3.8E+07

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QUALITY CONTROL
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02-08-05

Resolution Plot BB7

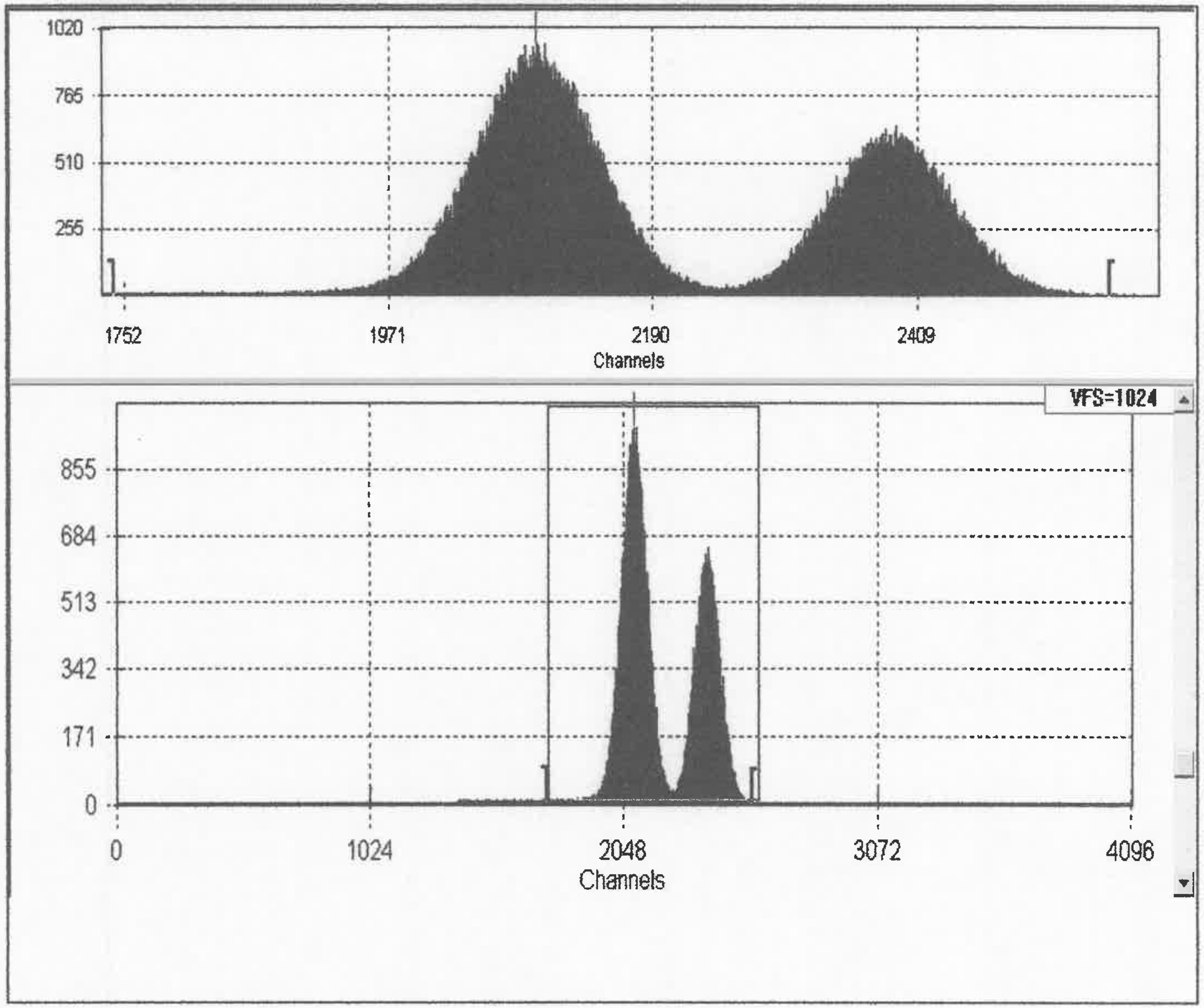
Wafer No.: 2435-2 **Thickness:** 61 um

JUNCTION

DET LINE: 308 KeV
SYSTEM: 284 KeV
CAL: 119 KeV

OHMIC

DET LINE: 310 KeV
SYSTEM: 284 KeV
CALC: 124 KeV



Source Am 241

Rise Time 1

Flat Top 0

BIAS VOLTS= 8 V **Leakage** 36 nA

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01/08/2005